

## CD4002M/CD4002C Dual 4-Input NOR Gate CD4012M/CD4012C Dual 4-Input NAND Gate

### General Description

These NOR and NAND gates are monolithic complementary MOS (CMOS) integrated circuits. The N- and P-channel enhancement mode transistors provide a symmetrical circuit with output swings essentially equal to the supply voltage. This results in high noise immunity over a wide supply voltage range. No DC power other than that caused by leakage current is consumed during static conditions. All inputs are protected against static discharge and latching conditions.

### Features

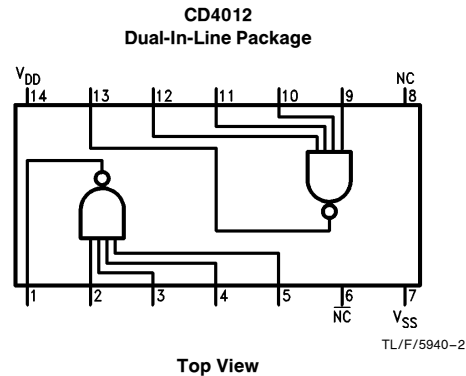
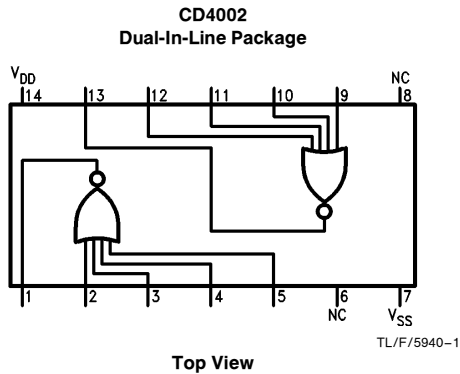
- Wide supply voltage range
- Low power
- High noise immunity

3.0V to 15V  
10 nW (typ.)  
0.45  $V_{DD}$  (typ.)

### Applications

- Automotive
- Data terminals
- Instrumentation
- Medical Electronics
- Alarm system
- Industrial controls
- Remote metering
- Computers

### Connection Diagrams



Order Number CD4002 or CD4012

**CD4002M/CD4002C Dual 4-Input NOR Gate**  
**CD4012M/CD4012C Dual 4-Input NAND Gate**

## Absolute Maximum Ratings (Note 1)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/Distributors for availability and specifications.

Voltage at Any Pin  $V_{SS} - 0.3V$  to  $V_{DD} + 0.3V$

Operating Temperature Range  
 CD4002M, CD4012M  $-55^{\circ}C$  to  $+125^{\circ}C$   
 CD4002C, CD4012C  $-40^{\circ}C$  to  $+85^{\circ}C$

Storage Temperature Range ( $T_S$ )  $-65^{\circ}C$  to  $+150^{\circ}C$

Power Dissipation ( $P_D$ )  
 Dual-In-Line 700 mW  
 Small Outline 500 mW

Operating Range ( $V_{DD}$ )  $V_{SS} + 3.0V$  to  $V_{SS} + 15V$

Lead Temperature ( $T_L$ )  
 (Soldering, 10 seconds)  $260^{\circ}C$

## DC Electrical Characteristics CD4002M, CD4012M

Symbol	Parameter	Conditions	Limits						Units	
			$-55^{\circ}C$		$+25^{\circ}C$			$+125^{\circ}C$		
			Min	Max	Min	Typ	Max	Min		Max
$I_{DD}$	Quiescent Device Current	$V_{DD} = 5.0V$ $V_{DD} = 10V$		0.05 0.1		0.001 0.001	0.05 0.1		3.0 6	$\mu A$ $\mu A$
$P_D$	Quiescent Device Dissipation/Package	$V_{DD} = 5.0V$ $V_{DD} = 10V$		0.25 1.0		0.005 0.01	0.25 1.0		15 60	$\mu W$ $\mu W$
$V_{OL}$	Output Voltage Low Level	$V_{DD} = 5.0V, V_I = V_{DD}, I_O = 0A$ $V_{DD} = 10V, V_I = V_{DD}, I_O = 0A$		0.05 0.05		0 0	0.05 0.05		0.05 0.05	V V
$V_{OH}$	Output Voltage High Level	$V_{DD} = 5.0V, V_I = V_{SS}, I_O = 0A$ $V_{DD} = 10V, V_I = V_{SS}, I_O = 0A$	4.95 9.95		4.95 9.95	5.0 10		4.95 9.95		V V
$V_{NL}$	Noise Immunity (All Inputs)	$V_{DD} = 5.0V, V_O = 3.6V, I_O = 0A$ $V_{DD} = 10V, V_O = 7.2V, I_O = 0A$	1.5 3.0		1.5 3.0	2.25 4.5		1.4 2.9		V V
$V_{NH}$	Noise Immunity (All Inputs)	$V_{DD} = 5.0V, V_O = 0.95V, I_O = 0A$ $V_{DD} = 10V, V_O = 2.9V, I_O = 0A$	1.4 2.9		1.5 3.0	2.25 4.5		1.5 3.0		V V
$I_{DN}$	Output Drive Current N-Channel (4002) (Note 2)	$V_{DD} = 5.0V, V_O = 0.4V, V_I = V_{DD}$ $V_{DD} = 10V, V_O = 0.5V, V_I = V_{DD}$	0.5 1.1		0.40 0.9	1.0 2.5		0.28 0.65		mA mA
$I_{DP}$	Output Drive Current P-Channel (4002) (Note 2)	$V_{DD} = 5.0V, V_O = 2.5V, V_I = V_{SS}$ $V_{DD} = 10V, V_O = 9.5V, V_I = V_{SS}$	-0.62 -0.62		-0.5 -0.5	-2.0 -1.0		-0.35 -0.35		mA mA
$I_{DN}$	Output Drive Current N-Channel (4012) (Note 2)	$V_{DD} = 5.0V, V_O = 0.4V, V_I = V_{DD}$ $V_{DD} = 10V, V_O = 0.5V, V_I = V_{DD}$	0.31 0.63		0.25 0.5	0.5 0.6		0.175 0.35		mA mA
$I_{DP}$	Output Drive Current P-Channel (4012) (Note 2)	$V_{DD} = 5.0V, V_O = 2.5V, V_I = V_{SS}$ $V_{DD} = 10V, V_O = 9.5V, V_I = V_{SS}$	-0.31 -0.75		-0.25 -0.6	-0.5 -1.2		-0.175 -0.4		mA mA
$I_I$	Input Current					10				pA

**Note 1:** "Absolute Maximum Ratings" are those values beyond which the safety of the device cannot be guaranteed. Except for "Operating Temperature Range" they are not meant to imply that the devices should be operated at these limits. The table of "Electrical Characteristics" provides conditions for actual device operation.

**Note 2:**  $I_{DN}$  and  $I_{DP}$  are tested one output at a time.

## DC Electrical Characteristics CD4002C, CD4012C

Symbol	Parameter	Conditions	Limits						Units	
			- 55°C		+ 25°C		+ 85°C			
			Min	Max	Min	Typ	Max	Min		Max
$I_{DD}$	Quiescent Device Current	$V_{DD} = 5.0V$ $V_{DD} = 10V$		0.5 5.0		0.005 0.005	0.5 5.0		15 30	$\mu A$ $\mu A$
$P_D$	Quiescent Device Dissipation/Package	$V_{DD} = 5.0V$ $V_{DD} = 10V$		2.5 50		0.025 0.05	2.5 50		75 300	$\mu W$ $\mu W$
$V_{OL}$	Output Voltage Low Level	$V_{DD} = 5.0V, V_I = V_{DD}, I_O = 0A$ $V_{DD} = 10V, V_I = V_{DD}, I_O = 0A$		0.05 0.05		0 0	0.05 0.05		0.05 0.05	V V
$V_{OH}$	Output Voltage High Level	$V_{DD} = 5.0V, V_I = V_{SS}, I_O = 0A$ $V_{DD} = 10V, V_I = V_{SS}, I_O = 0A$	4.95 9.95		4.95 9.95	5.0 10		4.95 9.95		V V
$V_{NL}$	Noise Immunity (All Inputs)	$V_{DD} = 5.0V, V_O \geq 3.6V, I_O = 0A$ $V_{DD} = 10V, V_O \geq 7.2V, I_O = 0A$	1.5 3.0		1.5 3.0	2.25 4.5		1.4 2.9		V V
$V_{NH}$	Noise Immunity (All Inputs)	$V_{DD} = 5.0V, V_O \leq 0.95V, I_O = 0A$ $V_{DD} = 10V, V_O \leq 2.9V, I_O = 0A$	1.4 2.9		1.5 3.0	2.25 4.5		1.5 3.0		V V
$I_{DN}$	Output Drive Current N-Channel (4002) (Note 2)	$V_{DD} = 5.0V, V_O = 0.4V, V_I = V_{DD}$ $V_{DD} = 10V, V_O = 0.5V, V_I = V_{DD}$	0.35 0.72		0.3 0.6	1.0 2.5		0.24 0.48		mA mA
$I_{DN}$	Output Drive Current N-Channel (4012) (Note 2)	$V_{DD} = 5.0V, V_O = 0.4V, V_I = V_{DD}$ $V_{DD} = 10V, V_O = 0.5V, V_I = V_{DD}$	0.145 0.3		0.12 0.25	0.5 0.6		0.095 0.2		mA mA
$I_{DP}$	Output Drive Current P-Channel (4002) (Note 2)	$V_{DD} = 5.0V, V_O = 2.5V, V_I = V_{SS}$ $V_{DD} = 10V, V_O = 9.5V, V_I = V_{SS}$	-0.35 -0.3		-0.3 -0.25	-2.0 -1.0		-0.24 -0.2		mA mA
$I_{DP}$	Output Drive Current P-Channel (4012) (Note 2)	$V_{DD} = 5.0V, V_O = 2.5V, V_I = V_{SS}$ $V_{DD} = 10V, V_O = 9.5V, V_I = V_{SS}$	-0.145 -0.35		-0.12 -0.3	-0.5 -1.2		-0.095 -0.24		mA mA
$I_I$	Input Current					10				pA

**Note 1:** "Absolute Maximum Ratings" are those values beyond which the safety of the device cannot be guaranteed. Except for "Operating Temperature Range" they are not meant to imply that the devices should be operated at these limits. The table of "Electrical Characteristics" provides conditions for actual device operation.

**Note 2:**  $I_{DN}$  and  $I_{DP}$  are tested one output at a time.

**AC Electrical Characteristics**\*  $T_A = 25^\circ\text{C}$ ,  $C_L = 15\text{ pF}$ , and input rise and fall times = 20 ns. Typical temperature coefficient for all values of  $V_{DD} = 0.3\%/^\circ\text{C}$ .

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>CD4002M</b>						
t <sub>PHL</sub>	Propagation Delay Time High to Low Level	V <sub>DD</sub> = 5.0V		35	50	ns
		V <sub>DD</sub> = 10V		25	40	ns
t <sub>PLH</sub>	Propagation Delay Time Low to High Level	V <sub>DD</sub> = 5.0V		35	50	ns
		V <sub>DD</sub> = 10V		25	40	ns
t <sub>THL</sub>	Transition Time High to Low Level	V <sub>DD</sub> = 5.0V		65	175	ns
		V <sub>DD</sub> = 10V		35	75	ns
t <sub>TLH</sub>	Transition Time Low to High Level	V <sub>DD</sub> = 5.0V		65	125	ns
		V <sub>DD</sub> = 10V		35	70	ns
C <sub>IN</sub>	Input Capacitance	Any Input		5.0		pF
<b>CD4002C</b>						
t <sub>PHL</sub>	Propagation Delay Time High to Low Level	V <sub>DD</sub> = 5.0V		35	120	ns
		V <sub>DD</sub> = 10V		25	65	ns
T <sub>PLH</sub>	Propagation Delay Time Low to High Level	V <sub>DD</sub> = 5.0V		35	80	ns
		V <sub>DD</sub> = 10V		25	55	ns
t <sub>THL</sub>	Transition Time High to Low Level	V <sub>DD</sub> = 5.0V		65	300	ns
		V <sub>DD</sub> = 10V		35	125	ns
t <sub>TLH</sub>	Transition Time Low to High Level	V <sub>DD</sub> = 5.0V		65	200	ns
		V <sub>DD</sub> = 10V		35	115	ns
C <sub>IN</sub>	Input Capacitance	Any Input		5.0		pF

\*AC Parameters are guaranteed by DC correlated testing.

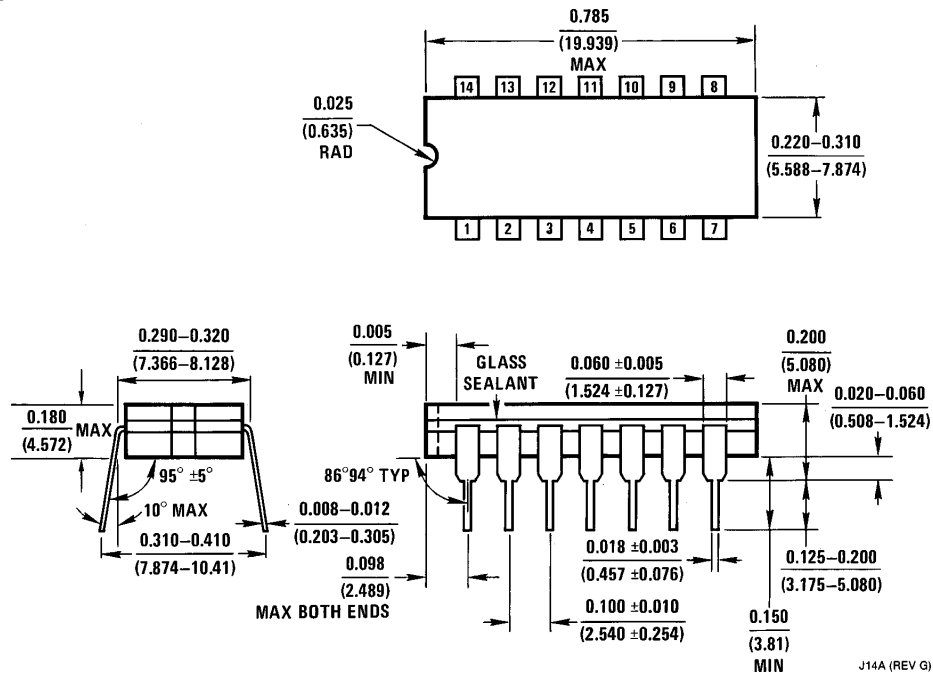
**AC Electrical Characteristics**\*  $T_A = 25^\circ\text{C}$ ,  $C_L = 15\text{ pF}$ , and input rise and fall times = 20 ns. Typical temperature coefficient for all values of  $V_{DD} = 0.3\%/^\circ\text{C}$ .

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>CD4012M</b>						
t <sub>PHL</sub>	Propagation Delay Time High to Low Level	V <sub>DD</sub> = 5.0V		50	75	ns
		V <sub>DD</sub> = 10V		25	40	ns
t <sub>PLH</sub>	Propagation Delay Time Low to High Level	V <sub>DD</sub> = 5.0V		50	75	ns
		V <sub>DD</sub> = 10V		25	40	ns
t <sub>THL</sub>	Transition Time High to Low Level	V <sub>DD</sub> = 5.0V		75	125	ns
		V <sub>DD</sub> = 10V		50	75	ns
t <sub>TLH</sub>	Transition Time Low to High Level	V <sub>DD</sub> = 5.0V		75	100	ns
		V <sub>DD</sub> = 10V		40	60	ns
C <sub>IN</sub>	Input Capacitance	Any Input		5.0		pF
<b>CD4012C</b>						
t <sub>PHL</sub>	Propagation Delay Time High to Low Level	V <sub>DD</sub> = 5.0V		50	100	ns
		V <sub>DD</sub> = 10V		25	50	ns
T <sub>PLH</sub>	Propagation Delay Time Low to High Level	V <sub>DD</sub> = 5.0V		50	100	ns
		V <sub>DD</sub> = 10V		25	50	ns
t <sub>THL</sub>	Transition Time High to Low Level	V <sub>DD</sub> = 5.0V		75	150	ns
		V <sub>DD</sub> = 10V		50	100	ns
t <sub>TLH</sub>	Transition Time Low to High Level	V <sub>DD</sub> = 5.0V		75	125	ns
		V <sub>DD</sub> = 10V		40	75	ns
C <sub>IN</sub>	Input Capacitance	Any Input		5.0		pF

\*AC Parameters are guaranteed by DC correlated testing.

**Note 1:** "Absolute Maximum Ratings" are those values beyond which the safety of the device cannot be guaranteed. Except for "Operating Temperature Range" they are not meant to imply that the devices should be operated at these limits. The table of "Electrical Characteristics" provides conditions for actual device operation.

**Physical Dimensions** inches (millimeters)

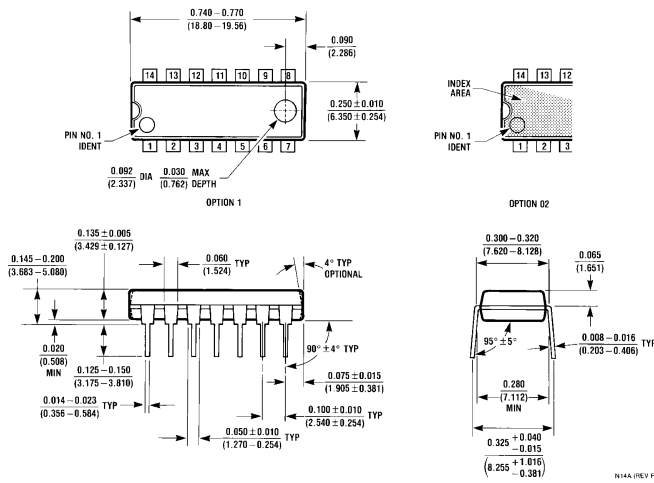


**Ceramic Dual-In-Line Package (J)**  
**Order Number CD4002MJ, CD4002CJ, CD4012MJ or CD4012CJ**  
**NS Package Number J14A**

J14A (REV G)

**CD4002M/CD4002C Dual 4-Input NOR Gate**  
**CD4012M/CD4012C Dual 4-Input NAND Gate**

**Physical Dimensions** inches (millimeters) (Continued)



**Molded Dual-In-Line Package (N)**  
**Order Number CD4002MN, CD4002CN, CD4012MN or CD4012CN**  
**NS Package Number N14A**

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